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(54) WAVELENGTH MULTIPLEXING OPTICAL NETWORK

(57)Abstract:

PROBLEM TO BE SOLVED: To section a faulty location by designating an optional section of an optical path and conducting the continuity test of the designated section without converting an optical signal in a wavelength multiplexing optical network.

SOLUTION: Optical path interface sections 2-1 to 2-20 are provided to sets of incoming and outgoing signal optical transmission lines 5-1 to 5-7, 6-1 to 6-6 through which each input output optical signals of wavelength multiplexing transmitters 1-1 to 1-6 are transmitted, the optical path interface sections are provided with 1st test signal transmission reception sections 3-1 to 3-6 connected via the optical transmission lines 6-1 to 6-6 in the station and a 2nd test signal transmission reception sections 4-1 to 4-20 in pairs with the optical path interface sections 2-1 to 2-20. The optical path interface sections apply routing or loopback to a test signal sent from the 1st or 2nd test signal transmission reception section to a desired output port of the

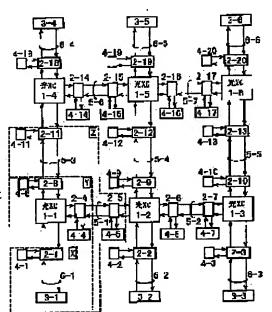
wavelength multiplex transmitter or the optical transmission line.

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